

5N80G-TA3-T-VB Datasheet

N-Channel 800V (D-S) Super Junction Power MOSFET

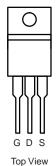
PRODUCT SUMMARY				
V _{DS} (V)	800			
R _{DS(on)} (Ω)	V _{GS} = 10 V	1.2		
Q _g (Max.) (nC)	200			
Q _{gs} (nC)	24			
Q _{gd} (nC)	110			
Configuration	Single			

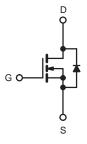
FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- · Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC









N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	800	V	
Gate-Source Voltage			V_{GS}	± 20	v	
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C	l _D	5		
		T _C = 100 °C		3.9	A	
Pulsed Drain Current ^a			I _{DM}	21		
Linear Derating Factor				1.5	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	770	mJ	
Repetitive Avalanche Current ^a			I _{AR}	7.8	А	
Repetitive Avalanche Energy ^a			E _{AR}	19	mJ	
Maximum Power Dissipation $T_C = 25 ^{\circ}C$			P _D	190	W	
Peak Diode Recovery dV/dt ^c			dV/dt	2.0	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	°C	
oldering Recommendations (Peak Temperature) for 10 s				300 ^d	7	
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in	
Mounting Torque				1.1	N⋅m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. V_{DD} = 50 V, starting T_J = 25 °C, L = 23 mH, R_g = 25 Ω , I_{AS} = 7.8 A (see fig. 12). c. I_{SD} \leq 7.8 A, dl/dt \leq 140 A/ μ s, V_{DD} \leq 600 V, T_J \leq 150 °C.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	40		
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.24	-	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.65		

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static						•	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		800	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C, I _D = 1 mA	-	0.98	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} :	= V _{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}		V _{GS} = ± 20 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		$V_{DS} = 800 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = 640 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 125 ^{\circ}\text{C}$		-	100 500	μA
Drain-Source On-State Resistance	R _{DS(on)}		$I_D = 3.7 \text{ A}^b$	_	1.2	-	Ω
Forward Transconductance	9fs		= 100 V, I _D = 3.7 A ^b	5.6	-	-	S
Dynamic	<u> </u>		_		L	1	
Input Capacitance	C _{iss}		V 0V		3100	-	
Output Capacitance	C _{oss}	1	$V_{GS} = 0 V$, $V_{DS} = 25 V$,	-	800	-	pF
Reverse Transfer Capacitance	C _{rss}	f = 1	f = 1.0 MHz, see fig. 5		490	-	•
Total Gate Charge	Qg			-	-	200	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$V_{GS} = 10 \text{ V}$ $I_{D} = 3.8 \text{ A}, V_{DS} = 400 \text{ V},$ see fig. 6 and 13 ^b		-	24	
Gate-Drain Charge	Q_{gd}				=	110	
Turn-On Delay Time	$t_{d(on)}$				19	-	ns
Rise Time	t _r	$V_{DD} = 400 \text{ V, } I_{D} = 3.8 \text{ A,}$ $R_{g} = 6.2 \Omega, R_{D} = 52 \Omega$ see fig. 10^{b}		ı	38	-	
Turn-Off Delay Time	$t_{d(off)}$			ı	120	-	
Fall Time	t _f			-	39	-	
Internal Drain Inductance	L_D	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	
Internal Source Inductance	L _S			-	13	-	- nH
Drain-Source Body Diode Characteristic	s					•	
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	5.0	_
Pulsed Diode Forward Current ^a	I _{SM}			-	-	21	A
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = 3.8 A, V _{GS} = 0 V ^b		-	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 3.8 A, dl/dt = 100 A/μs ^b		-	650	980	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	3.8	5.7	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_Γ				L _D)	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 µs; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

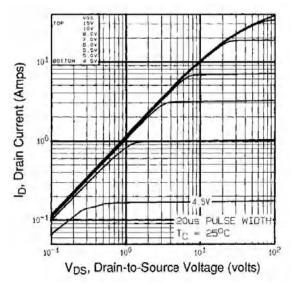


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

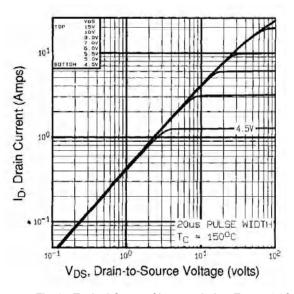


Fig. 2 - Typical Output Characteristics, T_C = 150 °C

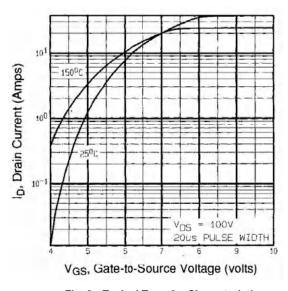


Fig. 3 - Typical Transfer Characteristics

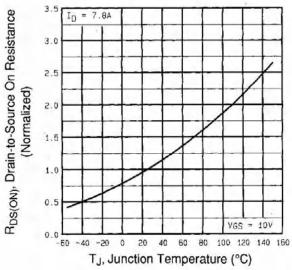


Fig. 4 - Normalized On-Resistance vs. Temperature



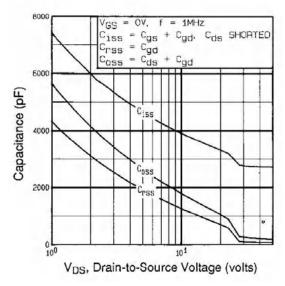


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

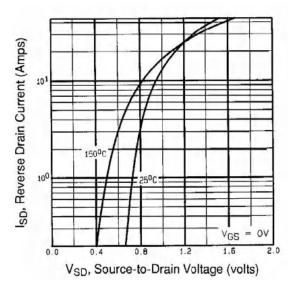


Fig. 7 - Typical Source-Drain Diode Forward Voltage

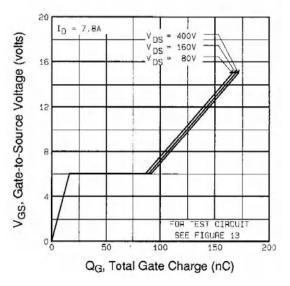


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

4

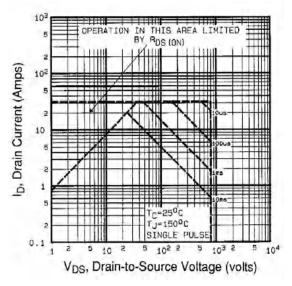


Fig. 8 - Maximum Safe Operating Area



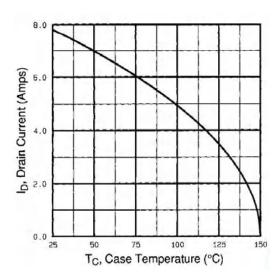


Fig. 9 - Maximum Drain Current vs. Case Temperature

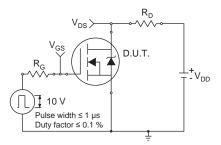


Fig. 10a - Switching Time Test Circuit

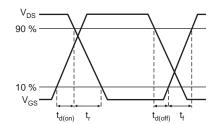


Fig. 10b - Switching Time Waveforms

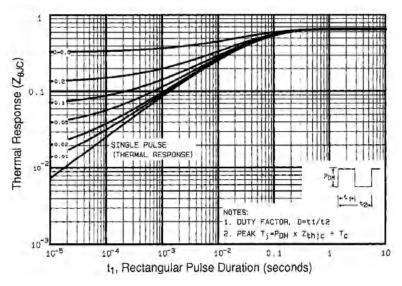


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



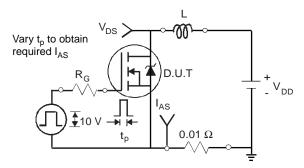


Fig. 12a - Unclamped Inductive Test Circuit

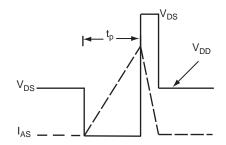


Fig. 12b - Unclamped Inductive Waveforms

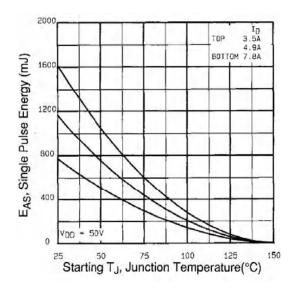


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

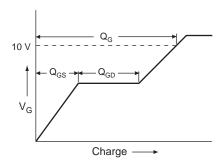


Fig. 13a - Basic Gate Charge Waveform

6

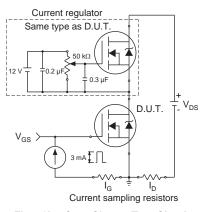
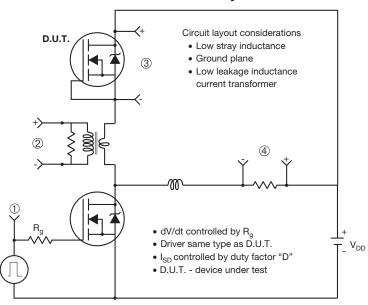


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



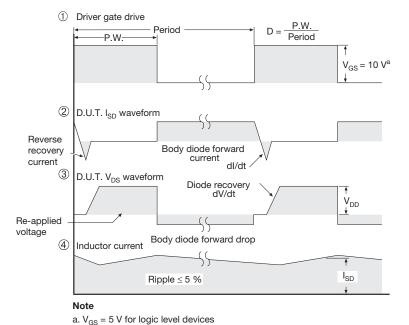
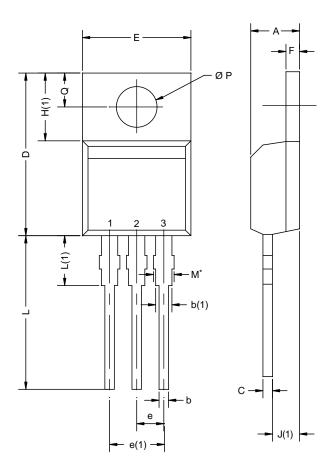


Fig. 14 - For N-Channel



TO-220AB



	MILLIN	IETERS	INC	HES	
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØΡ	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
FCN: X12-0208-Rev. N. 08-Oct-12					

ECN: X12-0208-Rev. N, 08-Oct-12

DWG: 5471

Notes

 * M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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